

DOCKET NO: 287800US26PCT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :  
MASAYUKI OIKAWA, ET AL. : EXAMINER: CHAN, CEDRIC A.  
SERIAL NO: 10/574,286 :  
FILED: MARCH 31, 2006 : GROUP ART UNIT: 1797  
FOR: INSPECTION METHOD AND :  
INSPECTION ASSISTING DEVICE FOR  
QUARTZ PRODUCT OF  
SEMICONDUCTOR PROCESSING  
APPARATUS

AMENDMENT UNDER 37 C.F.R. §1.111

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated February 22, 2010, please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 9 of this paper.